

*Excellence in Electronics***TYPE
6AH6WA**

The 6AH6WA is a heater-cathode type, high transconductance, sharp cut-off pentode of miniature construction designed for use as a wide band or IF amplifier. It will maintain its emission and freedom from excessive cathode interface resistance even after long periods of operation under cut-off conditions. It is designed for dependable operation under conditions of shock and vibration usually found in mobil and aircraft application. The heater-cathode construction is designed to withstand many thousands of cycles of intermittent operation.

MECHANICAL DATA**ENVELOPE:** T-5 1/2 Glass**BASE:** Miniature Button 7-Pin**TERMINAL CONNECTIONS:**

Pin 1 Grid #1
Pin 2 Grid #3
Pin 3 Heater
Pin 4 Heater

Pin 5 Plate
Pin 6 Grid #2
Pin 7 Cathode

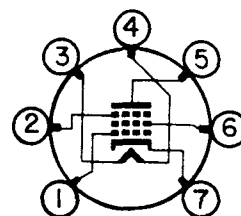
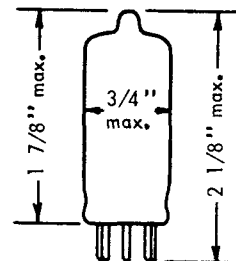
MECHANICAL RATINGS:

Maximum Impact Acceleration (Shock Test—Note 3)
Maximum Vibrational Acceleration (96 Hour Fatigue Test—Note 4)
Maximum Bulb Temperature

450 G
2.5 G
180 °C

MOUNTING POSITION: Any**ELECTRICAL DATA**

CAUTION-----To Electronic Equipment Design Engineers. Special attention should be given to the temperature at which the tubes are to be operated. Reliability will be seriously impaired if maximum bulb temperature is exceeded. The life expectancy may be reduced if conditions other than those specified for life test are imposed on the tube and will be reduced appreciably if maximum ratings are exceeded. Both reliability and performance will be jeopardized if filament voltage ratings are exceeded. Life and reliability of performance are closely related to the degree that regulation of the heater voltage is maintained at its center rated value.



BOTTOM VIEW

7BK

**RATINGS AND
NORMAL OPERATION:**MIL-E-1
SYMBOLDESIGN
MINIMUMNORMAL
TEST
CONDITIONS
(Note 6)NORMAL
OPERATION
(Note 5)DESIGN
MAXIMUMMIL-E-1
UNITS

Heater Voltage (Note 7)

Ef:

5.7

6.3

6.3

6.9

V

Plate Voltage

Eb:

300

300

330

Vdc

Grid #1 Voltage

Ec1:

0

0

Vdc

Grid #2 Voltage

Ec2:

150

150

165

Vdc

Grid #3 Voltage

Ec3:

0

0

Vdc

Plate Dissipation

Pp:

3.0

3.3

W

Grid #2 Dissipation

Pg2:

0.38

0.45

W

Heater-Cathode Voltage

Ehk:

-200

100

+200

v

Cathode Current

Ik:

12.5

28

mA_{dc}

Cathode Resistance

Rk:

160

ohms

Plate Current (1)

Ib(1):

10

mA_{dc}

Grid #2 Current

Ic2:

2.5

mA_{dc}

Transconductance (1)

S_m(1):

9000

μmhos

Plate Resistance

rp:

0.5

Meg.

Tentative Data

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RECEIVING TUBE AND SEMICONDUCTOR OPERATIONS



RELIABLE PENTODE

ELECTRICAL DATA (Cont'd.)

CHARACTERISTICS AND QUALITY CONTROL TESTS (Note 1)

TEST	CONDITIONS	AQL %	MIL-E-1 SYMBOL	MIN	LAL	BOGIE	UAL	MAX	ALD	MIL-E-1 UNITS
MEASUREMENTS ACCEPTANCE TESTS PART 1		Combined AQL=1.0% excluding Mechanical and Inoperatives								
Heater Current:		0.65	If:	420	432	450	468	480	36	mA
Heater-Cathode Leakage:	Ehk=+100 Vdc Ehk=-100 Vdc	0.65	Ihk: Ihk:					15		μ Adc μ Adc
Grid Current:	Rg1=1.0 Meg.	0.65	Ic (1):					-2.0		μ Adc
Plate Current (1):		0.65	Ib (1):	7.5	8.7	10.0	11.3	12.5	2.5	mAdc
Plate Current (2):	Ec1=10.0 Vdc	0.65	Ib (2):					30		μ Adc
Transconductance (1):		0.65	Sm (1):	7000	8000	9000	10000	11000	2000	μ mhos
Screen Grid Current:		0.65	Ic2:	1.5	1.9	2.5	3.1	3.5	1.4	mAdc
Continuity and Shorts (Inoperatives):		0.4								
Mechanical:	Envelope T-5 1/2 (6-2)									
MEASUREMENTS ACCEPTANCE TESTS PART 2										
Insulation of Electrodes:	Ef=6.3 V Eg1-all=-100 Vdc Ep-all=-300 Vdc	2.5	Rg1-all: Rp-all:	100 100						Meg. Meg.
Plate Current (3):	Ec1=-5.0 Vdc	2.5	Ib (3):	5						μ Adc
Transconductance (2):	Ef=5.7 V (Note 8)	2.5	Δ_{Ef} Sm (2):					15		%
Grid Emission:	Ef=7.5 V; preheat 5 minutes at Ec1=0 Vdc; Test at Ec1=-10 Vdc	2.5	Ic1(2):					-2.0		μ Adc
RF Noise:	Esig=35 mVac; Ck=0.2 μ f	2.5	EB:					5		VU
Noise and Microphonics:	Ef=6.3 Vdc; Ebb=Ecc2=300 Vdc; Ec1=0; Rk=200 ohms; Ec3 to ground; Rp=10,000 ohms; Rg2=60,000 ohms; Cg2=2 μ f; Ck=1000 μ f; Ecal=300 mVac	2.5	EB:					17		VU
Capacitance:			Cgp:					0.035		μ f
Capacitance:	Note 2	6.5	Cin:	8.0		10		12		μ f
Capacitance:			Cout:	3.0		4.5		6		μ f
Low Pressure Voltage Breakdown:	Pressure=55 $\pm$ 5 mmHg; Voltage=500 Vac	6.5								
Vibration (2):	F=25 cps; G=2.5; Rp=2000 ohms; Ck=1000 μ f	2.5	Ep:					100		mVac
DEGRADATION RATE ACCEPTANCE TESTS										
Shock:	Hammer Angle=30°; Ehk=+100 Vdc; (Note 3)	20								
Fatigue:	96 Hours; G=2.5 Fixed Frequency; F=25 min., 60 max. (Note 4)	6.5								
Post Shock and Fatigue Test End Points:										
Vibration (2):	F=25 cps; G=2.5; Rp=2000 ohms; Ck=1000 μ f		Ep:					200		mVac
Heater-Cathode Leakage:	Ehk=+100 Vdc Ehk=-100 Vdc		Ihk: Ihk:					30 30		μ Adc μ Adc
Change in Transconductance (1) of individual tubes:			$\Delta_{\dagger}$ Sm (1):					20		%

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REMOVING TUBE AND SEMICONDUCTOR OPERATIONS



RELIABLE PENTODE

ELECTRICAL DATA (Cont'd.)

CHARACTERISTICS AND QUALITY CONTROL TESTS (Note 1) (cont'd.)

TEST	CONDITIONS	AQL %	MIL - E - 1 SYMBOL	MIN	MAX	MIL - E - 1 UNITS	Allowable Defects per Characteristic 1st Sample	Combined Samples
DEGRADATION RATE ACCEPTANCE TESTS (cont 'd.)								
Grid Current (1):		----	Ic1:	----	-4.0	μ Adc		
Miniature Tube Base Strain:		----	----	----	----	----		
Glass Strain (Thermal Shock)		2.5	----	----	----	----		
ACCEPTANCE LIFE TESTS								
Heater Cycling Life Test:	Ef= 7.5V; Eb= Ec1= Ec2= Ec3= 0V; Ehk=+ 100 Vdc; 1 min. on, 4 min. off.	1.0	----	----	----	----		
Heater Cycling Life Test End Points:								
Heater -Cathode Leakage:	Ehk=+ 100 Vdc Ehk=-100 Vdc	----	Ihk: Ihk:	----	30 30	μ Adc μ Adc		
1 Hour Stability Life Test:	TA= Room; Ehk=+ 135 Vdc; Rg1= 0.1 meg. min.	----	----	----	----	----		
1 Hour Stability Life Test End Points:								
Change in Transcon- ductance (1) of in- dividual tubes:	(Typical Sample Size= 50 tubes)	1.0	Δ_f Sm (1):	----	10	%		
100 Hour Survival Rate Life Test:	TA= Room; Ehk=+ 135 Vdc; Rg1= 0.1 Meg. Min.	----	----	----	----	----		
100 Hour Survival Rate Life Test End Points:	(Typical Sample Size= 200 tubes)	----	----	----	----	----		
Continuity and Shorts (Inoperatives):		0.65	----	----	----	----		
Transconductance (1):		1.0	Sm (1):	6300	----	μ mhos		
Intermittent High Temperature Life Test:	T Bulb=+ 180 °C; Ehk=+ 135 Vdc; Rg1= 0.1 Meg. Min.	----	----	----	----	----		
500 Hour Intermittent High Temperature Life Test End Points:	(Typical Sample Size= 20 tubes 1st sample; 40 tubes 2nd sample).							
Inoperatives:		----	----	----	----	----	1	3
Grid Current (1):		----	Ic (1):	0	-2.0	μ Adc	1	3
Heater Current:		----	If:	410	490	mA	1	3
Change in Transcon- ductance (1) of in- dividual tubes:		----	Δ_f Sm (1):	----	20	%	1	3
Transcon- ductance (2):	(Note 8)	----	Δ_{Ef} Sm (2):	----	15	%	2	5
Heater -Cathode Leakage:	Ehk=+ 100 Vdc Ehk=-100 Vdc	----	Ihk: Ihk:	----	20 20	μ Adc μ Adc	1	3
Electrode Insula- tion:								
g1-all		----	Rg1-all:	50	----	Meg.		
p-all		----	Rp-all:	50	----	Meg.	2	5
Transconductance (1) average change:		----	Avg. Δ_f Sm (1):	----	15	%	---	---
Total Defectives		----	----	----	----	----	4	8



RELIABLE PENTODE

ELECTRICAL DATA (Cont'd.)

CHARACTERISTICS AND QUALITY CONTROL TESTS (Note 1) (cont'd.)

TEST	CONDITIONS	AQL %	MIL - E - 1 SYMBOL	MIN	MAX	MIL - E - 1 UNITS	Allowable Defects per Characteristic 1st Sample Combined Samples	
ACCEPTANCE LIFE TESTS (cont 'd.)								
1000 Hour Intermittent Life Test End Points:	(Typical Sample Sizes=20 tubes 1st sample;40 tubes 2nd sample).	----	----	----	----	----	---	---
Inoperatives:		----	----	----	----	----	2	5
Grid Current (1):		----	Ic1 (1):	0	-2.0	μ Adc	2	5
Heater Current:		----	If:	410	490	mA	2	5
Change in transcon- ductance (1) of in - dividual tubes:		----	Δ _f Sm (1):	----	20	%	2	5
Heater -Cathode Leakage:	Ehk=+100 Vdc Ehk=-100 Vdc	----	Ihk: Ihk:	----	20 20	μ Adc μ Adc	2	5
Total Defectives:		----	----	----	----	----	5	10
500 Hour Cathode Interface Resis - tance Life Test:	TA=Room; Ef= 7.5 Vac; Ehk= 0; g1, g2, g3 and P Floating	----	----	----	----	----	---	---
500 Hour Cathode Interface Resis - tance Life Test End Points:	(Typical Sample Size= 20 tubes 1st sample, 40 tubes 2nd sample)	----	----	----	----	----	---	---
Interface Resis - tance:		----	ri:	----	25	ohms	1	3

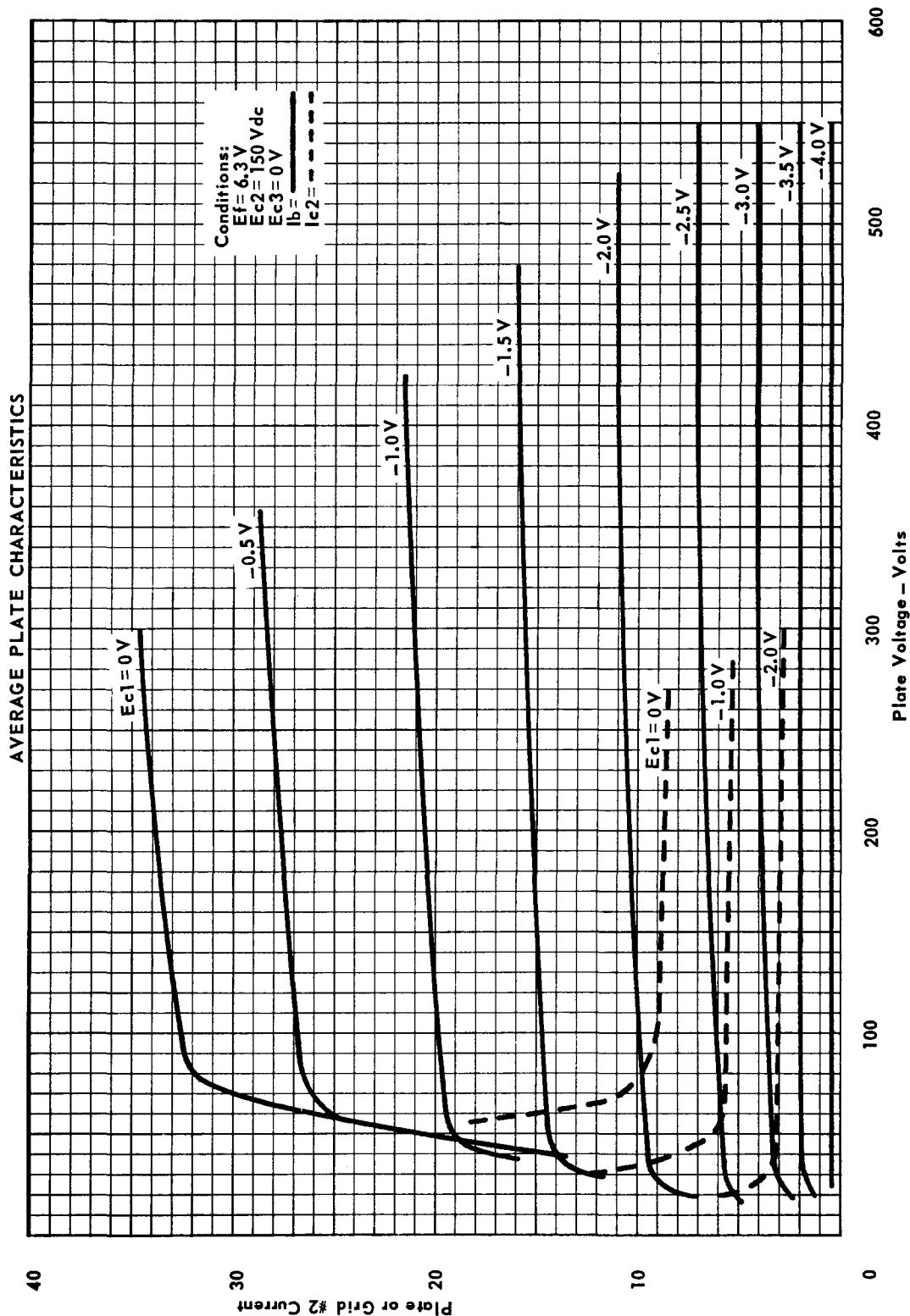
NOTES

- Note 1: Characteristics, Quality Control Test Procedures, and Inspection Levels are made according to the appropriate paragraphs of MIL-E-1, "Inspection Instructions for Electron Tubes" and MIL-STD-105A.
- Note 2: With cylindrical shield no. 316 connected to cathode lead.
- Note 3: Test Conditions and Acceptance Criteria per Shock Test Procedures of MIL-E-1 basic specifications.
- Note 4: Test Conditions and Acceptance Criteria per Fatigue Test Procedure of MIL-E-1 basic specifications.
- Note 5: These normal values represent conditions at which control of reliability may be expected.
- Note 6: These normal test conditions are used for all characteristic tests unless otherwise stated under individual test items.
- Note 7: For most applications the performance will not be adversely affected by $\pm 10\%$ heater voltage variation, but when the application can provide a closer control of heater voltage, an improvement in reliability will be realized.
- Note 8: Change of transconductance for individual tubes from that value measured at Ef=6.3 V to that value measured at Ef=5.7 V.

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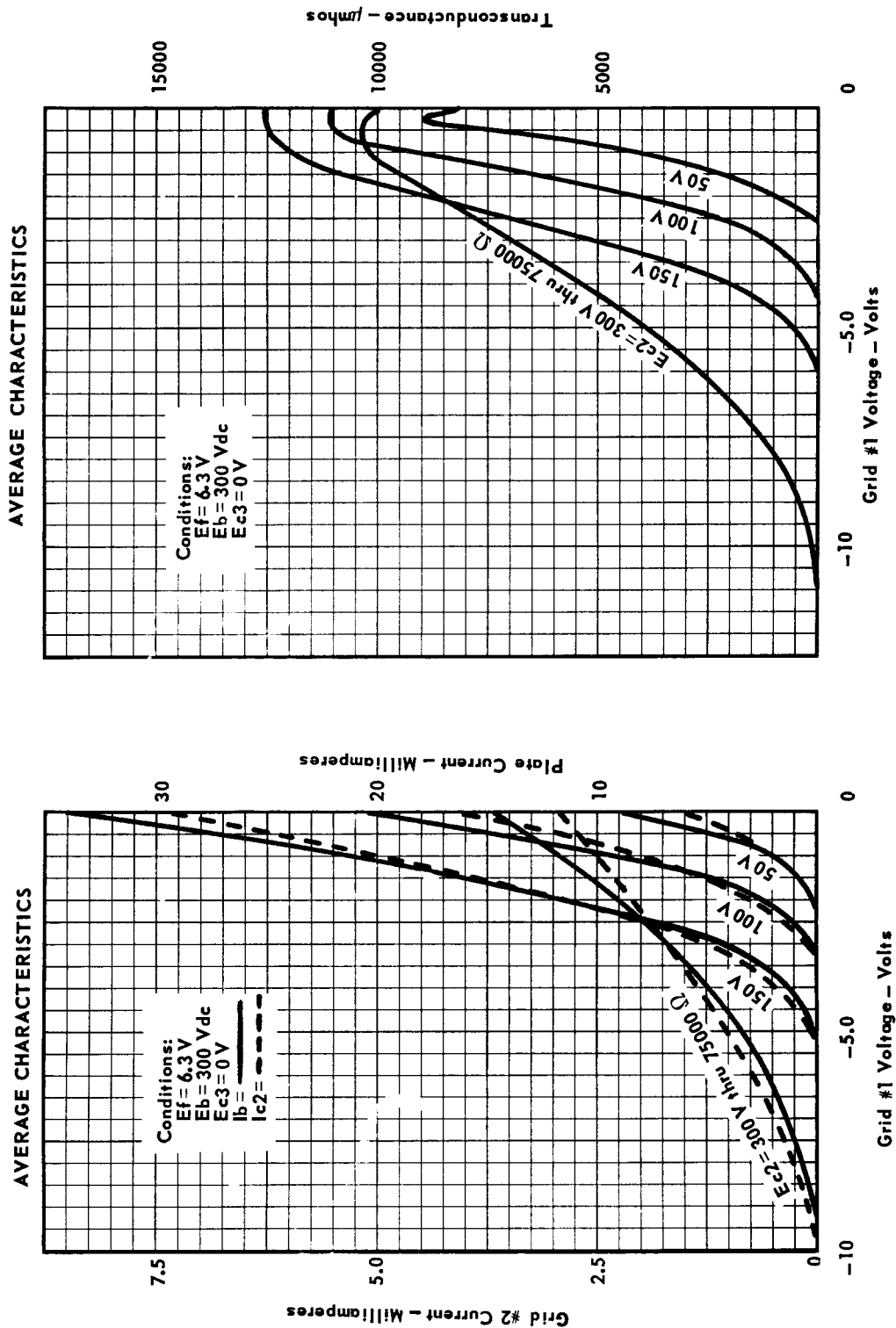
RECEIVING TUBE AND SEMICONDUCTOR OPERATIONS

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 RECEIVING AND CATHODE RAY TUBE OPERATIONS